

PRODUCT CHANGE NOTIFICATION

Ref Nr: EBR-0176-2026060401

Date: Jun 4, 2026

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TO: Customers who may concern

FROM: Product Marketing, CPC

HEREWITH YOU ARE INFORMED OF OUR INTENTION TO DISCONTINUE SOME ESD PARTS

DESCRIPTION:

To enhance surge withstand capability, we will optimize the internal structure of ESD SJD12A36L01 on the new production line starting Dec 30, 2026. Products manufactured with the optimized structure are fully backward compatible with the existing version and feature improved surge performance. Their appearance, dimensions and electrical parameters including capacitance, leakage current and breakdown voltage remain unchanged and fully comply with the current specifications. The new structure will supersede the original one. Please refer to the attached comparison report for details.

REASONS: To enhance surge withstand capability

EXPECTED INFLUENCE ON PERFORMANCE: None

EXPECTED INFLUENCE ON QUALITY AND RELIABILITY: None

CHANGE:

Quality REPORTS available: Available based on customers' request

SAMPLES available: Any sample request please kindly contact with our sales

Implementation date: **Dec 30, 2026**

Type identification after change: Lot number

SUGGESTION FOR ALTERNATIVE PRODUCTS: None

Quality Manager:

Signature:



Product Manager:

Signature:



Sales Manager:

Signature:



Date: 2026-6-24

Date: 2026-6-24

Date: 2026-6-24

FOR MORE INFORMATION, CONTACT: YAGEO sales contact window

RETURN YOUR COMMENTS BEFORE: Jun 30, 2026

Remarks: If customer has no feedback about this change before the customer response date, the change will be regarded as approved by customer automatically.

Comments:

Date:

Function:

Signature:

Comparison Report

Product Family: ☐TVS ☐TSS ☒ESD ☐MOV ☐GDT ☐SPG ☐PTC

File Name: SJD12A36L01 Comparison Report

Report: BZ26052601

Version	V1	Date of updated	2026-05-26	Date of released	2026-05-26
Prepared By	Fangfang Peng	Checked By	Xiaoyi Gong	Ack. By	Yihu Pan
Requirements	☒ Refer to the< Product Contrast Test Specification > ☐ According to customers' specific requirements.				

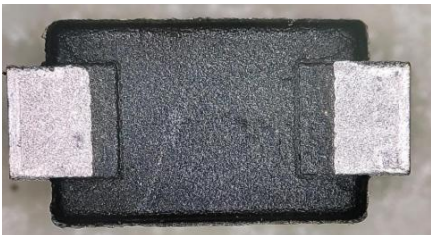
Part I: Sample Info.

Grouping	Part#	Remark	Comparing Items
Sample A	SJD12A36L01	Present Structure	1.Exterior/Dimensions;
Sample B	SJD12A36L01	Changed Structure	2.Inner Structure; 3.Surge Capacity;

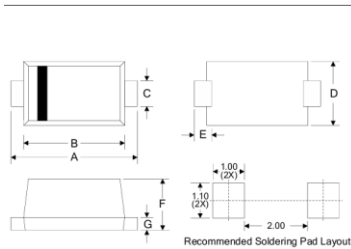
Remark: The results are limited to the samples in this report and only for reference. For any question, please just contact the report output department.

Part II: Content

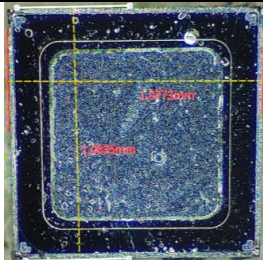
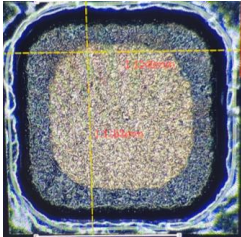
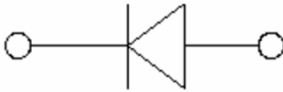
2.1 Exterior Appearance

Items	Sample A	Sample B
Top		
Bottom		
Side		
Marking	MP	MP

2.2 Exterior Dimensions

Specification					<table><tr><th rowspan="3">Symbol</th><th colspan="4">Dimension</th></tr><tr><th colspan="2">Millimeters</th><th colspan="2">Inches</th></tr><tr><th>Min.</th><th>Max.</th><th>Min.</th><th>Max.</th></tr><tr><td>A</td><td>3.50</td><td>3.90</td><td>0.138</td><td>0.154</td></tr><tr><td>B</td><td>2.60</td><td>3.00</td><td>0.102</td><td>0.118</td></tr><tr><td>C</td><td>0.75</td><td>1.10</td><td>0.030</td><td>0.043</td></tr><tr><td>D</td><td>1.60</td><td>2.00</td><td>0.063</td><td>0.079</td></tr><tr><td>E</td><td colspan="2">0.80Typ.</td><td colspan="2">0.031Typ.</td></tr><tr><td>F</td><td>0.90</td><td>1.40</td><td>0.035</td><td>0.055</td></tr><tr><td>G</td><td>0.12</td><td>0.22</td><td>0.005</td><td>0.009</td></tr></table>	Symbol	Dimension				Millimeters		Inches		Min.	Max.	Min.	Max.	A	3.50	3.90	0.138	0.154	B	2.60	3.00	0.102	0.118	C	0.75	1.10	0.030	0.043	D	1.60	2.00	0.063	0.079	E	0.80Typ.		0.031Typ.		F	0.90	1.40	0.035	0.055	G	0.12	0.22	0.005	0.009
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Item	Sample A		Sample B																																																		
A (3.50-3.90mm)	3.55		3.81																																																		
B (2.60-3.00mm)	2.81		2.82																																																		
C (0.75-1.10mm)	0.99		1.00																																																		
D (1.60-2.00mm)	1.81		1.81																																																		
E (Typ.0.80)	0.95		0.75																																																		
F(0.90-1.40mm)	0.98		1.23																																																		
G (0.12-0.22mm)	0.15		0.17																																																		

2.3 Inner Structure

Items	Sample A	Sample B
X-ray Top		
Chip Side		
Chip Size	Area : 1.0835mm*1.0773mm	Area : 1.1240mm *1.1263mm
Chip quantity	1pcs	1pcs
Circuit		

2.4 10/1000 μ s surge capability

100%IPP 3.5A	Sample A	Sample B
	NG/Total	NG/Total
100%	0/10	0/10
150%	8/10	0/10
170%		0/10
180%		5/10

2.6 Conclusion

Confirming Items	Specification	Sample A	Sample B
Part#	SJD12A36AL01	SJD12A36AL01	SJD12A36AL01
Marking	MP	MP	MP
Length*width*height	Min.:3.50*1.60*0.90 Max.:3.90*2.00*1.40	3.55*1.81*0.98	3.81*1.81*1.23
Capacitance (Cj)	Max:242pF	218-221pF	229-240pF
Leakage Current (IR)	Max.: 1uA@VR=36V	0.006-0.029uA	0.005-0.017uA
Breakdown Voltage (VB)	40.04-44.13V	40.5-41.14V	41.43-42.36V
10/1000 us	IPP:100%	150%	170%
Chip specification	/	(1) Area size: 1.0835mm*1.0773mm (2) Chip quantity:1pcs (3) Chip technology: Planar process (4) A piece of discrete chip	(1) Area size: 1.1240mm *1.1263mm (2) Chip quantity:1pcs (3) Chip technology: GPP process (4)A piece of discrete chip

In summary, Sample A and Sample B show consistent performance in appearance, dimensions, capacitance, leakage current and breakdown voltage, and both comply with specification requirements. Sample B delivers superior surge withstand capability at 10/1000 μ s compared with Sample A. Accordingly, Sample B is qualified to replace Sample A.

Part III: Detailed Data

3.1 Purpose of experiment

Through comparative testing and analyzing, we can understand advantages and disadvantages of different samples and give readers a reference.

3.2 VB&IR&Cj Comparison.

NO.	Pin-Out	Sample A			Sample B		
		VB (V)	IR (uA)	Cj(pF)	VB (V)	IR (uA)	Cj(pF)
1#	Pin1-Pin2	40.90	0.006	218	41.61	0.005	229
2#	Pin1-Pin2	40.81	0.024	221	42.36	0.009	240
3#	Pin1-Pin2	41.14	0.011	221	42.03	0.005	230
4#	Pin1-Pin2	40.90	0.026	220	42.28	0.006	230
5#	Pin1-Pin2	40.50	0.029	220	41.62	0.017	229
6#	Pin1-Pin2	40.56	0.024	220	42.17	0.027	215
7#	Pin1-Pin2	40.51	0.030	221	41.84	0.025	220
8#	Pin1-Pin2	41.19	0.018	220	41.86	0.007	229
9#	Pin1-Pin2	40.94	0.014	221	41.43	0.023	220
10#	Pin1-Pin2	40.90	0.006	220	42.38	0.006	222

3.3 10/1000us Surge Capacity Comparison.

NO.	Pin-Out	Sample A				Sample B			
		VC	After test			VC	After test		
		VC(V)	VB (V)	IR (uA)	Cj(pF)	VC(V)	VB (V)	IR (uA)	Cj(pF)
1#	Pin1-Pin2	48.71	41.42	0.003	218	48.16	41.21	0.027	229
2#	Pin1-Pin2	47.79	42.36	0.029	221	49.20	41.58	0.004	240
3#	Pin1-Pin2	48.44	40.88	0.007	221	48.71	42.34	0.002	230
4#	Pin1-Pin2	47.92	40.79	0.019	220	48.86	42.01	0.029	230
5#	Pin1-Pin2	47.76	41.11	0.024	220	47.98	42.25	0.004	229
6#	Pin1-Pin2	47.37	40.88	0.029	220	48.92	41.60	0.022	215
7#	Pin1-Pin2	47.79	40.47	0.003	221	48.34	42.15	0.007	220
8#	Pin1-Pin2	47.79	40.52	0.030	220	48.34	41.82	0.023	229
9#	Pin1-Pin2	48.65	40.48	0.007	221	48.22	41.84	0.010	220
10#	Pin1-Pin2	48.10	41.16	0.015	220	49.56	41.42	0.003	222

Part IV: Testing Equipment Info.

No.	Device Name	Device Type	Calibration Expiry Date	Device Picture
1	Testing machine (QDC-007)	VR66	2027-09-13	
2	Power testing machine	VC6700	2027-12-22	
3	2D Measuring Projector	MY3020	2026-06-14	